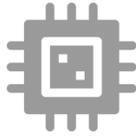
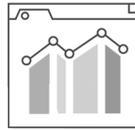




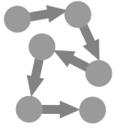
Test



Program



Diagnose



Sequence



Integrate



Deploy



## ScanExpress Runner™ **Boundary-Scan Test Executive**

### Features

- Built-in test sequencer that automatically and dynamically executes independent test steps
- Intelligent fault detection and isolation to the net and pin level
- Truth Table Diagnostics with pattern and waveform views
- Integrated test debugger with breakpoints, looping, and single-stepping
- User-programmable general purpose input/output (GPIO) signal control
- Built-in analytics data collection with chart and graph display
- In-System-Programming (ISP) of CPLDs, flash, and serial EEPROM devices
- Executes JTAG Embedded Test (JET) steps for extended test coverage and embedded functional testing
- Interfaces with LabVIEW, LabWindows/CVI, Keysight VEE, Visual Basic, and other third-party test executives
- Supports Corelis high-performance JTAG controllers
- Compatible with the complete Corelis ScanExpress family of products
- Works with Microsoft Windows

### Benefits

- Combines boundary-scan test, in-system programming, & JET functional test
- Simplifies boundary-scan test execution
- Increases yields and decreases test time
- Speeds test, diagnosis, and repair of faulty circuit boards

### Applications

#### Hardware Development

Use boundary-scan to test, debug, and verify prototype hardware, then reuse the same tests for full-scale production.

#### Hardware Production

The graphical user interface is both straightforward and powerful, enabling execution of complete tests with the click of a button.

#### Service & Repair

Re-use the same tests from development and production to reduce troubleshooting and repair times.

Efficiency in engineering means managing your most precious resources: time and effort. Automated testing is essential and boundary-scan is a critical component; no other structural test system provides the same value.

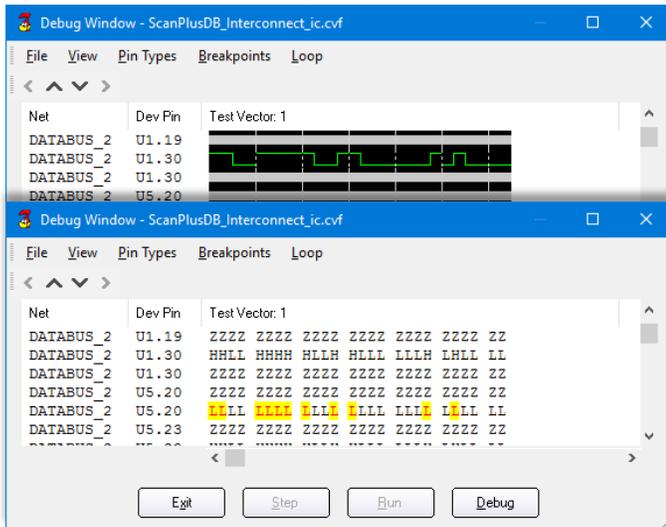
When down to the wire, your boundary-scan test system needs to be built both for ease-of-use and reliability; a robust and powerful mechanism to ensure that no matter the state of production, all boundary-scan tests can be quickly and faithfully executed to maintain forward momentum.

**ScanExpress Runner™** is a fully featured JTAG test executive; a modern software application that provides the capabilities and options necessary to ensure a smooth and complete testing process. With visual, one-touch execution of ScanExpress test sequences and interface support for all major test platforms, ScanExpress Runner stands proud as the reliable daily workhorse of the ScanExpress software family.



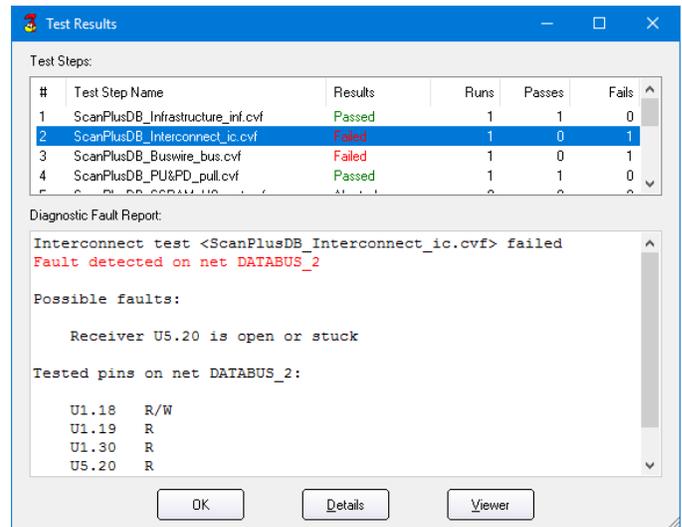
The ScanExpress Runner™ test executive enables execution of IEEE-1149.1 & IEEE-1149.6 (JTAG) boundary-scan tests with an easy-to-use graphical user interface (GUI) and advanced test execution features. Runner comes standard with Basic Diagnostic (BDO) functionality and can be enhanced with the optional Advanced Diagnostics (ADO) module for detailed pin and net level diagnostics.

### Basic Diagnostics (BDO)



Basic Diagnostics (BDO) module displays complete Truth Table Diagnostic test results in pattern or waveform format.

### Advanced Diagnostics (ADO)



Advanced Diagnostics (ADO) module adds detailed descriptions of detected faults down to the pin and net level.

## Combined Structural and Functional Test

ScanExpress Runner executes both boundary-scan structural test steps generated by ScanExpress TPG™ and CPU-based functional real-time tests created by ScanExpress JET™. Whether on the desktop, test bench, or in the field, a complete JTAG test strategy can be achieved with just a host PC, Corelis JTAG controller, and ScanExpress Runner software<sup>1</sup>.

## Third Party Applications

In addition to the intuitive operator interface, ScanExpress Runner includes a third party application interface consisting of DLLs, command-line functions, and LabVIEW virtual instrument drivers. ScanExpress Runner integrates easily and conveniently into off-the-shelf test executive solutions and custom, in-house software solutions alike.

## Data Analytics

ScanExpress Runner can record test analytics—including test results, diagnostics, metrics, and more in a

centralized database. Data can be exported or filtered and displayed with an included chart generator.

## Test File Formats

ScanExpress Runner supports test step files created by Corelis' own boundary-scan tools as well as test step formats created by third party vector generators for JTAG testing and in-system-programming.

Supported test step file formats include:

### Compact Vector Format (CVF)

ScanExpress TPG™ generated test step files for world-class boundary-scan testing.

### JTAG Embedded Test (JET)

ScanExpress JET™ test step files<sup>1</sup> for JTAG functional tests using embedded CPUs.

### Flash Programming Information (FPI)

ScanExpress Flash Generator™ files for flash and EEPROM in-system programming.

## Serial Vector Format (SVF) & Standard Test and Programming Language (STAPL)

Standard vector files for FPGA, CPLD, and microcontroller programming.

## Extensible Test Format (ETF)

Script-based test steps for utility functions and interfacing with third party command-line applications.

## Ordering Information

### Part Number - 20650

For more information, or to order this product online, please visit our website at [www.corelis.com](http://www.corelis.com)



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<sup>1</sup>ScanExpress JET test step execution requires a JET family support package license.  
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